Self Protected Very Low I_q High Side Driver with Analog Current Sense

The NCV84160 is a fully protected single channel high side driver that can be used to switch a wide variety of loads, such as bulbs, solenoids, and other actuators. The device incorporates advanced protection features such as active inrush current management, over–temperature shutdown with automatic restart and an overvoltage active clamp. A dedicated Current Sense pin provides precision analog current monitoring of the output as well as fault indication of short to V_D , short circuit to ground and ON and OFF state open load detection. An active high Current Sense Disable pin allows all diagnostic and current sense features to be disabled.

Features

- Short Circuit Protection with Inrush Current Management
- CMOS (3 V / 5 V) Compatible Control Input
- Very Low Standby Current
- Very Low Current Sense Leakage
- Proportional Load Current Sense
- Current Sense Disable
- Off State Open Load Detection
- Output Short to V_D Detection
- Overload and Short to Ground Indication
- Thermal Shutdown with Automatic Restart
- Undervoltage Shutdown
- Integrated Clamp for Inductive Switching
- Loss of Ground and Loss of V_D Protection
- ESD Protection
- Reverse Battery Protection
- AEC-Q100 Qualified
- This is a Pb–Free Device

Typical Applications

- Switch a Variety of Resistive, Inductive and Capacitive Loads
- Can Replace Electromechanical Relays and Discrete Circuits
- Automotive / Industrial

FEATURE SUMMARY

Max Supply Voltage	V_D	41	V
Operating Voltage Range	V_D	4.5 to 28	V
R _{DSon} (max) T _J = 25°C	R _{ON}	160	mΩ
Output Current Limit (typical)	I _{LIM}	12	Α
OFF-state Supply Current (typical)	I _{D(off)}	0.01	μΑ



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SOIC-8 CASE 751 STYLE 11

MARKING DIAGRAM

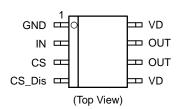


84160 = Specific Device Code A = Assembly Location

Y = Year WW = Work Week ■ = Pb-Free Package

(Note: Microdot may be in either location)

PIN CONNECTIONS



ORDERING INFORMATION

Device	Package	Shipping [†]
NCV84160DR2G	SOIC-8 (Pb-Free)	2500 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

Block Diagram & Pin Configuration

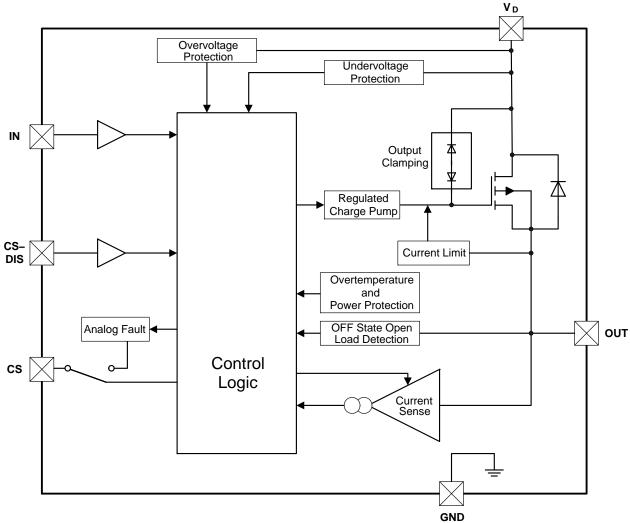


Figure 1. Block Diagram

Table 1. SO8 PACKAGE PIN DESCRIPTION

Pin#	Symbol	Description
1	GND	Ground
2	IN	Logic Level Input
3	CS	Analog Current Sense Output
4	CS_DIS	Active High Current Sense Disable
5	V_D	Supply Voltage
6	OUT	Output
7	OUT	Output
8	V_D	Supply Voltage

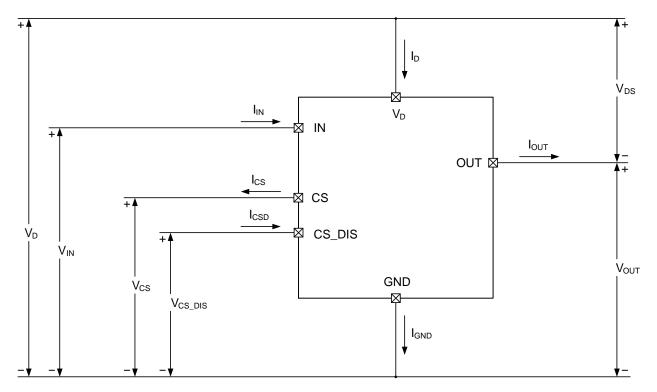


Figure 2. Voltage and Current Conventions

Table 2. Connection suggestions for unused and or unconnected pins

Connection	Input	Output	Current Sense	Current Sense Enable
Floating	Х	Х	Not Allowed	X
To Ground	Through 10 kΩ resistor	Not Allowed	Through 1 kΩ Resistor	Through 10 k Ω resistor

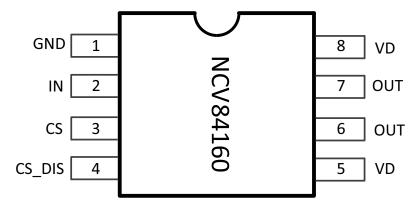


Figure 3. Pin Configuration (top view)

ELECTRICAL SPECIFICATIONS

Table 3. MAXIMUM RATINGS

Rating	Symbol	Min	Max	Unit	
DC Supply Voltage	V _D	-0.3	41	V	
Peak Transient Input Voltage (Load Dump 46 V, V _D = 14 V, ISO16750–2: 2012 Test B)	V _{peak}		48	V	
Input Voltage	V _{in}	-10	10	V	
Input Current	l _{in}	– 5	5	mA	
Reverse Ground Pin Current	I _{GND}		-200	mA	
Output Current (Note 2)	l _{out}	-6	Internally Limited	Α	
CS Current	I _{CS}		200	mA	
CS Voltage	V _{CS}	V _D -41	V _D	V	
CS_DIS Voltage	V _{CS_DIS}	-10	10	V	
CS_DIS Current	I _{CS_DIS}	-5	5	mA	
Power Dissipation T _c = 25°C (Note 4)	P _{tot}		1.49	W	
Electrostatic Discharge (HBM Model 100 pF / 1500 Ω) Input Current Sense Current Sense Enable Output V _D	V _{ESD}	4 3 4 3 3		DC kV kV kV kV	
Charge Device Model CDM-AEC-Q100-011		750		V	
Single Pulse Inductive Load Switching Energy (Note 1) (L = TBD mH, V_{bat} = 13.5 V; I_L = 6 A, T_{J_Start} = 150°C	E _{AS}		42.85	mJ	
Operating Junction Temperature	TJ	-40	+150	°C	
Storage Temperature	T _{storage}	-55	+150	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Not subjected to production testing

Table 4. THERMAL RESISTANCE RATINGS

Parameter	Symbol	Max. Value	Units
Thermal Resistance Junction-to-Lead Junction-to-Ambient (Note 3) Junction-to-Ambient (Note 4)	R _{θJL} R _{θJA} R _{θJA}	32 98 84	°C/W

^{2.} Reverse Output current has to be limited by the load to stay within absolute maximum ratings and thermal performance.

Min. pad size, 1 oz. Cu with backside plane covered with 1 oz. Cu (backside plane not electrically connected).
 2 cm² pad size, 1 oz. Cu with backside plane covered with 1 oz. Cu (backside plane not electrically connected).

ELECTRICAL CHARACTERISTICS (8 \leq V_D \leq 28 V; -40° C < T_J < 150 $^{\circ}$ C unless otherwise specified)

Table 5. POWER

				Value		
Rating	Symbol	Conditions	Min	Тур	Max	Unit
Operating Supply Voltage	V _D		4.5	-	28	V
Undervoltage Shutdown	V _{UV}			3.5	4.5	V
Undervoltage Shutdown Hysteresis	V _{UV_hyst}			0.5		V
On Resistance	R _{ON}	I _{out} = 1 A, T _J = 25°C			160	mΩ
		I _{out} = 1 A, T _J = 150°C			320	1
		I _{out} = 1 A, V _D = 5 V, T _J = 25°C			210	
Supply Current (Note 5)	I _D	OFF-state: V _D = 13 V, V _{in} = V _{out} = 0 V, Tj = 25°C		0.01	0.5	μΑ
		ON-state: $V_D = 13 \text{ V}$, $V_{in} = 5 \text{ V}$, $I_{out} = 0 \text{ A}$		1.9	3.5	mA
Output Leakage Current	I _{L(OFF)}	$V_{in} = V_{out} = 0 \text{ V}, V_D = 13 \text{ V}, T_j = 25^{\circ}\text{C}$			0.5	μΑ
		V _{in} = V _{out} = 0 V, V _D = 13 V, Tj = 125°C			0.5	1

^{5.} Includes PowerMOS leakage current.

Table 6. LOGIC INPUTS

				Value		
Rating	Symbol	Conditions	Min	Тур	Max	Unit
Input Voltage – Low	V _{in_low}				0.9	V
Input Current – Low	I _{in_low}	V _{in} = 0.9 V	1			μΑ
Input Voltage – High	V _{in_high}		2.1			V
Input Current – High	l _{in_high}	V _{in} = 2.2 V			10	μΑ
Input Hysteresis Voltage	V _{in_hyst}		0.2			V
Input Clamp Voltage	V _{in_cl}	I _{in} = 1 mA	12	13	14	V
		$I_{in} = -1 \text{ mA}$	-14	-13	-12	
CS_DIS Voltage - Low	V _{CS_DIS_LOW}				0.9	V
CS_DIS Current – Low	I _{CS_DIS_LOW}	V _{CSD} = 0.9 V	1			μΑ
CS_DIS Voltage - High	V _{CS_DIS_HIGH}		2.1			V
CS_DIS Current – High	I _{CS_DIS_HIGH}	V _{CSD} = 2.2 V			10	μΑ
CS_DIS Hysteresis Voltage	V _{CS_DIS_HYST}		0.2			V
CS_DIS Clamp Voltage	V _{CS_DIS_CL}	I _{CSD} = 1 mA	12	13	14	V
		I _{CSD} = -1 mA	-14	-13	-12	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

Table 7. SWITCHING CHARACTERISTICS $(T_J < 25^{\circ}C)$

			Value			
Rating	Symbol	Conditions	Min	Тур	Max	Unit
Turn-On Delay Time	t _{d_on}	to 10% Vout, $V_D = 13 \text{ V}$, $R_L = 13 \Omega$		10		μs
Turn-Off Delay Time	t _{d_off}	to 90% Vout, $V_D = 13 \text{ V}$, $R_L = 13 \Omega$		10		μs
Slew Rate On	dV _{out} /dt _{on}	10% to 80% Vout, V_D = 13 V, R_L = 13 Ω		0.7		V / μs
Slew Rate Off	dV _{out} /dt _{off}	90% to 10% Vout, V_D = 13 V, R_L = 13 Ω		0.7		V / μs
Turn-On Switching Loss (Note 6)	E _{on}	$V_D = 13 \text{ V}, R_L = 13 \Omega$		0.04		mJ
Turn-Off Switching Loss (Note 6)	E _{off}	$V_D = 13 \text{ V}, R_L = 13 \Omega$		0.04		mJ

^{6.} Not subjected to production testing

Table 8. OUTPUT DIODE CHARACTERISTICS

			Value			
Rating	Symbol	Conditions	Min	Тур	Max	Unit
Forward Voltage	V_{F}	$I_{out} = -1 \text{ A}, T_J = 150^{\circ}\text{C}, V_F = V_{out} - V_D$			0.7	V

Table 9. PROTECTION FUNCTIONS (Note 8)

				Value		
Rating	Symbol	Conditions	Min	Тур	Max	Unit
Temperature Shutdown (Note 7)	T _{SD}		150	175	200	°C
Temperature Shutdown Hysteresis (T _{SD} – T _R) (Note 7)	T _{SD_hyst}			7		°C
Reset Temperature (Note 7)	T _R		T _{RS} +1	T _{RS} +5		°C
Thermal Reset of CS_FAULT (Note 7)	T _{R_CS}		135			°C
DC Output Current Limit	I _{LIM_H}	V _D = 13 V	6	12	18	Α
		5 V < V _D < 28 V			18	Α
Short Circuit Current Limit during Thermal Cycling (Note 7)	I _{LIM_L}	$V_D = 13 \text{ V}$ $T_R < T_j < T_{SD}$		6.5		Α
Switch Off Output Clamp Voltage	V _{out_clamp}	$I_{out} = 1 A, V_{in} = 0 V, L = 20 mH$	V _D – 41	V _D – 45	V _D – 52	V
Overvoltage Protection	V _{OV}	$V_{in} = 0 \text{ V}, I_D = 20 \text{ mA}$	41	45	52	V
Output Voltage Drop Limitation	V _{DS_ON}	$I_{out} = 0.025 \text{ A}, -40^{\circ}\text{C} \le T_{J} \le 150^{\circ}\text{C}$		25		mV

Table 10. OPEN-LOAD DETECTION (8 \leq V $_D$ \leq 18 V)

			Value			
Rating	Symbol	Conditions	Min	Тур	Max	Unit
Open-load Off-State Detection Threshold	V _{OL}	V _{in} = 0 V	2	_	4	V
Open-load On-State Detection Threshold	l _{OL}	$V_{in} = 5 \text{ V}, I_{CS} = 5 \mu A$	0.5		5	mA
Open-load Detection Delay at Turn-Off	t _{d_OL_off}		100		800	μs
Off-State Output Current	I _{OLOFF1}	$V_{in} = 0 \text{ V}, V_{OUT} = V_{OL}$	-3		3	μΑ
Output rising edge to CS rising edge during open–load	t _{D_OL}	$V_{OUT} = 4 \text{ V}, V_{in} = 0 \text{ V},$ CS = 90% of V_{CS_HIGH}			20	μs

Not subjected to production testing.
 To ensure long term reliability during overload or short circuit conditions, protection and related diagnostic signals must be used together with a fitting hardware & software strategy. If the device operates under abnormal conditions, this hardware & software solution must limit the duration and number of activation cycles.

Table 11. CURRENT SENSE CHARACTERISTICS (8 \leq VD \leq 18 V)

			Value			
Rating	Symbol	Conditions	min typ		max	Unit
Current Sense Ratio	Κ ₀	$I_{out} = 0.025 \text{ A, CS} = 0.5 \text{ V,}$ $T_{J} = -40^{\circ}\text{C to } 150^{\circ}\text{C}$	260	490	760	
Current Sense Ratio	K ₁	$I_{out} = 0.35 \text{ A, CS} = 0.5 \text{ V,}$ $T_{J} = -40^{\circ}\text{C to } 150^{\circ}\text{C}$	310	465	620	
		$I_{out} = 0.35 \text{ A, CS} = 0.5 \text{ V,}$ $T_{J} = 25^{\circ}\text{C to } 150^{\circ}\text{C}$	360	465	545	
Current Sense Ratio Drift (Note 9)	ΔK ₁ / K ₁	$I_{out} = 0.35 \text{ A, CS} = 0.5 \text{ V,}$ $T_{J} = -40^{\circ}\text{C to } 150^{\circ}\text{C}$	-11		11	%
Current Sense Ratio	K ₂	I _{out} = 0.5 A, CS = 4 V, T _J = -40°C to 150°C	350	455	570	
		I _{out} = 0.5 A, CS = 4 V, T _J = 25°C to 150°C	380	455	530	
Current Sense Ratio Drift (Note 9)	$\Delta K_2 / K_2$	$I_D = 0.5 \text{ A}, T_J = -40^{\circ}\text{C} \text{ to } 150^{\circ}\text{C}$	-8		8	%
Current Sense Ratio	K ₃	I _{out} = 1.5 A, CS = 4 V, T _J = -40°C to 150°C	405	455	505	
		I _{out} = 1.5 A, CS = 4 V, T _J = 25°C to 150°C	415	455	495	
Current Sense Ratio Drift (Note 9)	$\Delta K_3 / K_3$	$I_D = 1.5 \text{ A}, T_J = -40^{\circ}\text{C to } 150^{\circ}\text{C}$	-4		4	%
Current Sense Leakage Current	CS _{Ilkg}	$I_{out} = 0 \text{ A, CS} = 0 \text{ V}$ $V_{CS_DIS} = 5 \text{ V, V}_{IN} = 0 \text{ V}$ $T_{J} = -40^{\circ}\text{C to } 150^{\circ}\text{C}$			1	μΑ
		$I_{out} = 0 \text{ A, CS} = 0 \text{ V}$ $V_{CS_DIS} = 0 \text{ V, V}_{IN} = 5 \text{ V}$ $T_{J} = -40^{\circ}\text{C to } 150^{\circ}\text{C}$			2	
		$I_{out} = 1 \text{ A, CS} = 0 \text{ V}$ $V_{CS_DIS} = 5 \text{ V, V}_{IN} = 5 \text{ V}$ $T_{J} = -40^{\circ}\text{C to } 150^{\circ}\text{C}$			1	
CS Max Voltage	CS _{Max}	R _{CS} = 10 KΩ, I _{OUT} = 1 A	5			V
Current Sense Voltage in Fault Condition (Note 10)	V _{CS_FAULT}	V_D = 13 V, R_{CS} = 3.9 k Ω		8		V
Current Sense Current in Fault Condition (Note 10)	I _{CS_FAULT}	$V_D = 13 \text{ V}, R_{CS} = 5 \text{ k}\Omega$		15		mA
CS_Dis Low to CS High Delay Time	t _{CS_HIGH1}	CS < 4 V, 0.025 A < I _{OUT} < 1.5 A I _{CS} = 90% of I _{CS} Max		40	100	μS
S_Dis High to CS Low Delay Time t_{CS_LOW1} $CS < 4 \text{ V}, 0.025 \text{ A} < I_{OL}$ $I_{CS} = 90\% \text{ of } I_{CS} \text{ I}$		CS < 4 V, 0.025 A < I _{OUT} < 1.5 A I _{CS} = 90% of I _{CS} Max		5	20	μS
V _{in} High to CS High Delay Time t _{CS_HIGH2}		CS < 4 V, 0.025 A < I _{OUT} < 1.5 A I _{CS} = 10% of I _{CS} Max	30		160	μS
V _{in} Low to CS Low Delay Time	t _{CS_LOO2}	CS < 4 V, 0.025 A < I _{OUT} < 1.5 A I _{CS} = 10% of I _{CS} Max		80	250	μS
Delay Time I _D Rising Edge to Rising Edge of CS	∆t _{CS_HIGH2}	$CS < 4 \text{ V}$, $I_{CS} = 90\%$ of I_{CS} Max, $I_{OUT} = 90\%$ of I_{OUTmax} , $I_{OUTmax} = 1.5 \text{ A}$			110	μs

^{9.} Not subjected to production testing.10. The following fault conditions are: Overtemperature, Power Limitation, and OFF State Open–Load Detection.

Table 12. TRUTH TABLE

Conditions	Input	Output	CS (V _{CS_DIS} = 0 V) (Note 11)	
Normal Operation	L H	L H	$0 \\ I_{CS} = I_{OUT}/K_{NOMINAL}$	
Over-temperature	L H	L L	0 V _{CS_FAULT}	
Under-voltage	L H	L L	0 0	
Overload	H H	H (no active current mgmt) Cycling (active current mgmt)	I _{CS} = I _{OUT} /K _{NOMINAL} V _{CS_FAULT}	
Short circuit to Ground	L H	L L	0 Vcs_fault	
OFF State Open-Load	L	Н	V _{CS_FAULT}	

^{11.} If the V_{CS_DIS} is high, the Current Sense output is at a high impedance, its potential depends on leakage currents and external circuitry.

ELECTRICAL CHARACTERISTICS WAVEFORMS AND GRAPHS

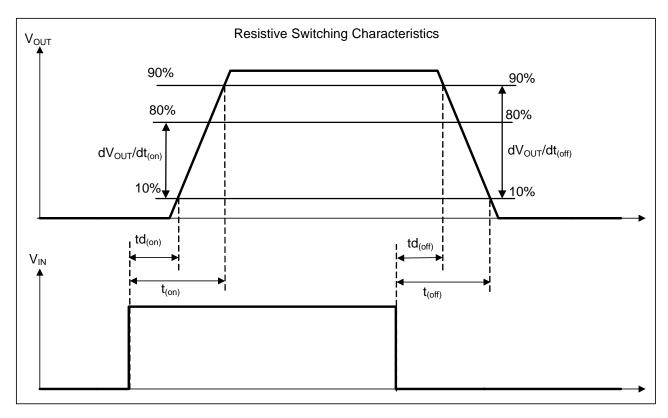


Figure 4. Switching Characteristics

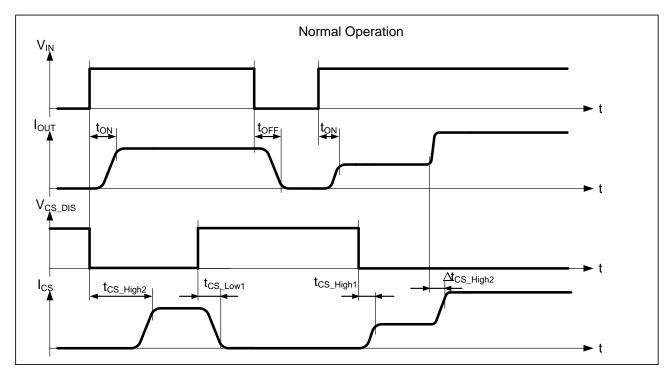


Figure 5. Normal Operation with Current Sense Timing Characteristics

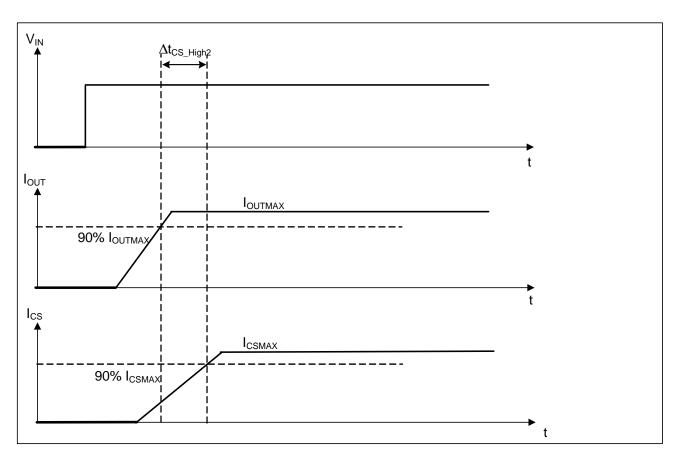


Figure 6. Delay Response from rising edge of IOUT and rising edge of CS (for CS_EN = 5V)

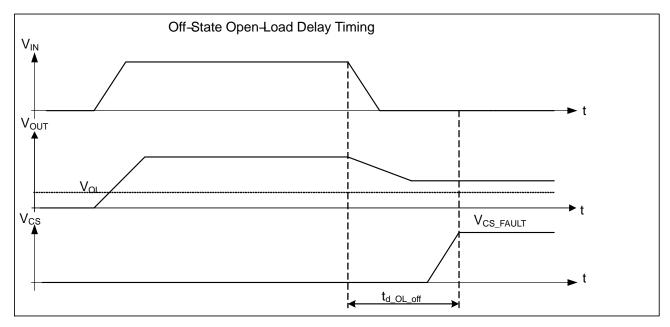


Figure 7. OFF-State Open-Load Flag Delay Timing

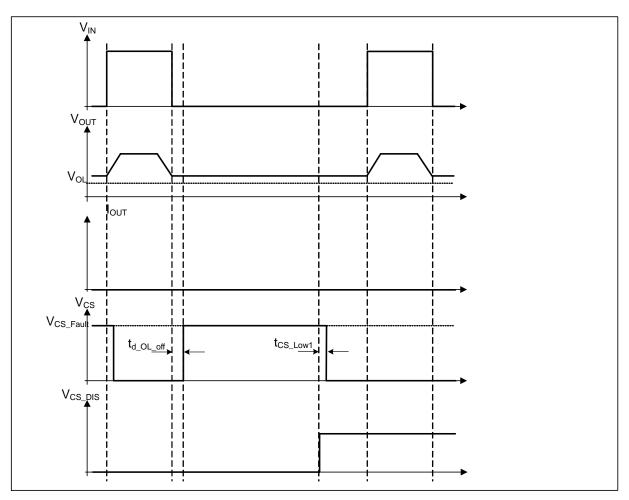


Figure 8. Off-State Open-Load with added external components

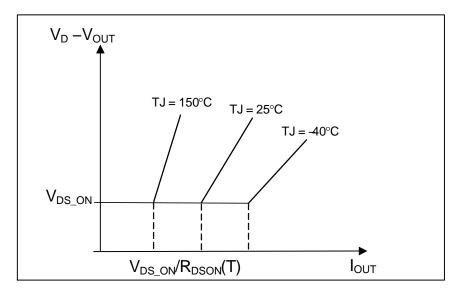


Figure 9. Voltage Drop Limitation for VDS_ON

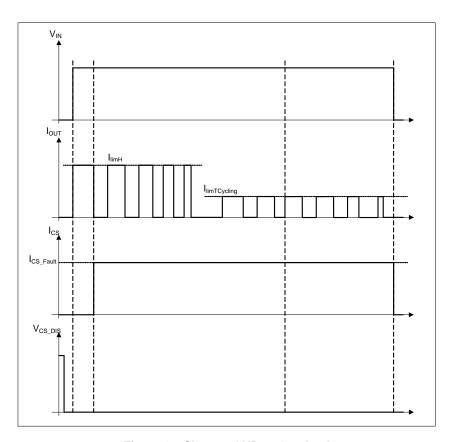


Figure 10. Short to GND or Overload

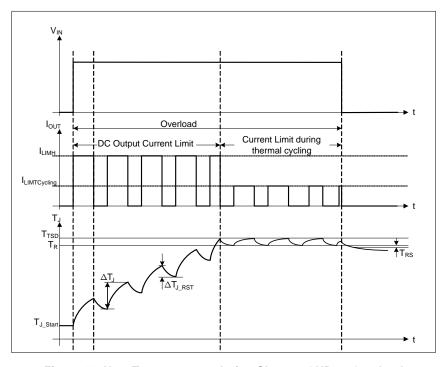


Figure 11. How T_J progresses during Short to GND or Overload

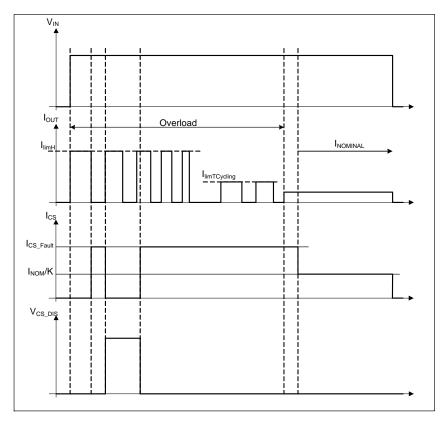


Figure 12. Discontinuous Overload or Short to GND

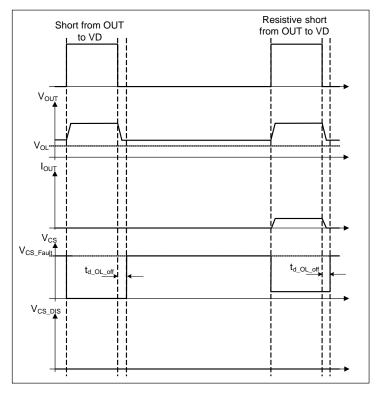


Figure 13. Short Circuit from OUT to VD

ISO 7637-2: 2011(E) PULSE TEST RESULTS

ISO 7637-2:2011	Test Severity Levels					
Test Pulse	III	IV	Delays and Impedance	# of Pulses or Test Time	Pulse / Burst rep. time	
1	-112	-150	2 ms, 10 Ω	500 pulses	0.5 s	
2a	55	112	$0.05~\text{ms},2~\Omega$	500 pulses	0.5 s	
3a	-165	-220	0.1 us, 50 Ω	1 h	100 ms	
3b	112	150	0.1 us, 50 Ω	1 h	100 ms	
ISO 7637-2:2011	Test R	esults				
Test Pulse	III	IV				
1		А				
2a	Α	E				
3a		А				
3b		А				
Class			Functional	Status		
Α	All functions of a device perform as designed during and after exposure to disturbance.					
В	All functions of a device perform as designed during exposure. However, one or more of them can go beyond specified tolerance. All functions return automatically to within normal limits after exposure is removed. Memory functions shall remain class A.					
С	One or more functions of a device do not perform as designed during exposure but return automatically to normal operation after exposure is removed.					
D	One or more functions of a device do not perform as designed during exposure and do not return to normal operation until exposure is removed and the device is reset by simple "operator/use" action.					
E	One or more functions of a device do not perform as designed during and after exposure and cannot be returned to proper operation without replacing the device.					

Application Information

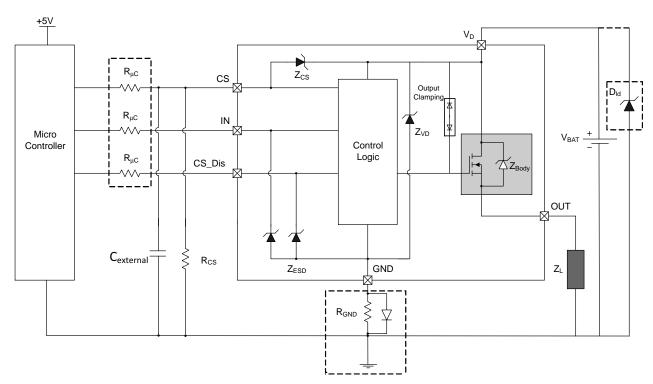


Figure 14. Application Schematic

Loss of Ground Protection

When device or ECU ground connection is lost and load is still connected to ground, the device will turn the output OFF. In loss of ground state, the output stage is held OFF independent of the state of the input. Input resistors are recommended between the device and microcontroller.

Reverse Battery Protection

Solution 1: Resistor in the GND line only (no parallel Diode)
The following calculations are true for any type of load.

In the case for no diode in parallel with R_{GND} , the calculations below explain how to size the resistor.

Consider the following parameters: $-I_{GND}$ Maximum = 200 mA for up to $-V_D = 32$ V.

Where $-I_{GND}$ is the DC reverse current through the GND pin and $-V_D$ is the DC reverse battery voltage.

$$-I_{GND} = \frac{-V_D}{R_{GND}}$$
 (eq. 1)

Since this resistor can be used amongst multiple High–Side devices, please take note the sum of the maximum active GND currents ($I_{GND(On)max}$) for each device when sizing the resistor. Please note that if the microprocessor GND is not shared by the device GND, then R_{GND} produces a shift of ($I_{GND(On)max} * R_{GND}$) in the input thresholds and CS output values. If the calculated power dissipation leads to too large of a resistor size or several devices have to share the same resistor, please look at the second solution for Reverse Battery Protection. Refer to the figure below for selecting the proper R_{GND} .

NCV84160 Reverse Battery Considerations Normal Operation VIN = 5 V, Reverse Battery = 32 V

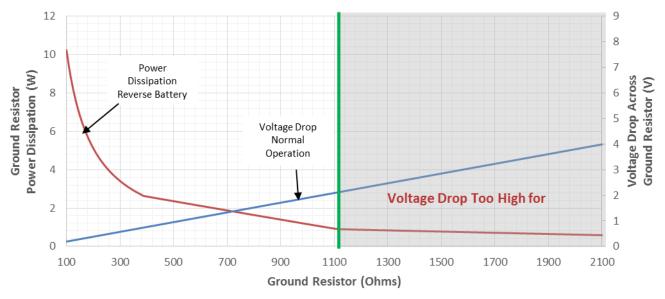


Figure 15. Reverse Battery R_{GND} Considerations

Solution 2: Diode (DGND) in parallel with RGND in the ground line.

A resistor value of $R_{GND}=1$ kOhm should be selected and placed in parallel to D_{GND} if the device drives an inductive load. The diode (D_{GND}) provides a ~600–700 mV shift in the input threshold and current sense values if the micro controller ground is not common to the device ground. This shift will not vary even in the case of multiple high–side devices using the same resistor/diode network.

Undervoltage Protection

The device has two under–voltage threshold levels, V_{D_MIN} and V_{UV} . Switching function (ON/OFF) requires supply voltage to be at least V_{D_MIN} . The device features a lower supply threshold V_{UV} , above which the output can remain in ON state. While all protection functions are guaranteed when the switch is ON, diagnostic functions are operational only within nominal supply voltage range V_{D} .

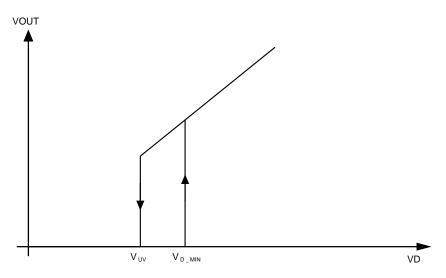


Figure 16. Undervoltage Behavior

Overvoltage Protection

The NCV84160 has two Zener diodes ZV_D and ZCS, which provide integrated overvoltage protection. ZVD protects the logic block by clamping the voltage between supply pin V_D and ground pin GND to VZV_D. ZCS limits voltage at current sense pin CS to V_D – VZCS. The output power MOSFET's output clamping diodes provide protection by clamping the voltage across the MOSFET (between V_D pin and OUT pin) to VCLAMP. During overvoltage protection, current flowing through ZVD, ZCS and the output clamp must be limited. Load impedance ZL limits the current in the body diode ZBody. In order to limit the current in ZV_D a resistor, RGND (150 Ω), is required in the GND path. External resistors RCS and RSENSE limit the current flowing through ZCS and out of the CS pin into the micro-controller I/O pin. With RGND, the GND pin voltage is elevated to V_D - VZV_D when the supply voltage V_D rises above VZV_D. ESD diodes ZESD pull up the voltage at logic pins IN, CS_Dis close to the GND pin voltage V_D -VZV_D. External resistors RIN, and RCS_DIS are required to limit the current flowing out of the logic pins into the micro-controller I/O pins. During overvoltage exposure, the device transitions into a self-protection state, with automatic recovery after the supply voltage comes back to the normal operating range. The specified parameters as well as short circuit robustness and energy capability cannot be guaranteed during overvoltage exposure.

Overload Protection

Current limitation as well as over-temperature shutdown mechanisms are integrated into the NCV84160 to provide protection from overload conditions such as bulb inrush or short to ground.

Current Limitation

In case of overload, the NCV84160 limits the current in the output power MOSFET to a safe value. Due to high power dissipation during current limitation, the device's junction temperature increases rapidly. In order to protect the device, the output driver is shut down by one of the two over–temperature protection mechanisms. The output current limitation level is dependent on the drain–to–source voltage of the power MOSFET. If the input remains active during the shutdown, the output power MOSFET will automatically be re–activated after a minimum OFF time or when the junction temperature returns to a safe level.

Output Clamping with Inductive Load Switch Off:

The output voltage V_{OUT} drops below GND potential when switching off inductive loads. This is because the inductance develops a negative voltage across the load in response to a decaying current. The integrated clamp of the device clamps the negative output voltage to a certain level relative to the supply voltage V_{BAT}. During output clamping with inductive load switch off, the energy stored in the inductance is rapidly dissipated in the device resulting in high power dissipation. This is a stressful condition for the device and the maximum energy allowed for a given load inductance should not be exceeded in any application.

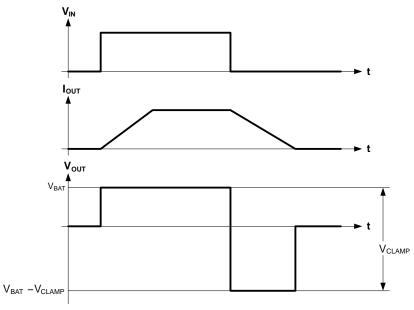


Figure 17. Inductive Load Switching

Open Load Detection in OFF State

Open load diagnosis in the OFF-state can be performed by activating an external resistive pull-up path (RPU) to VBAT. To calculate the pull-up resistance, external leakage currents (designed pull-down resistance, humidity-induced leakage etc) as well as the open load threshold voltage VOL have to be taken into account.

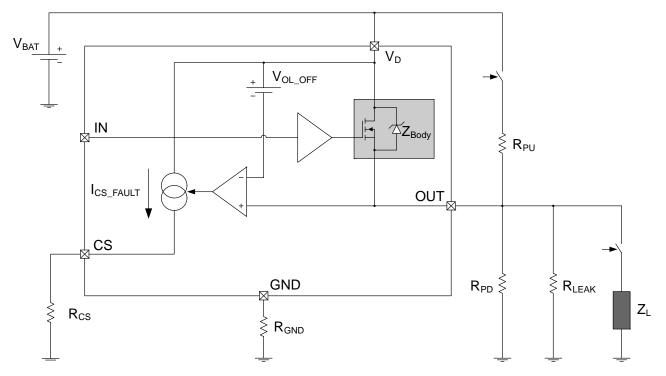


Figure 18. Off State Open Load Detection Circuit

Current Sense in PWM Mode

While operating in PWM mode, the current sense functionality can be used, but the timing of the input signal and the response time of the current sense need to be considered. When operating in PWM mode, the following performance is to be expected. The CS_DIS pin should be left low to eliminate any unnecessary delay time to the circuit. When $V_{\rm IN}$ switches from low to high, there will be

a typical delay (tCS_High2) before the current sense responds. Once this timing delay has passed, the rise time of the current sense output (Δt CS_High2) also needs to be considered. When $V_{\rm IN}$ switches from high to low a delay time (tCS_Low1) needs to be considered. As long as these timing delays are allowed, the current sense pin can be operated in PWM mode.

Package and PCB Thermal Data

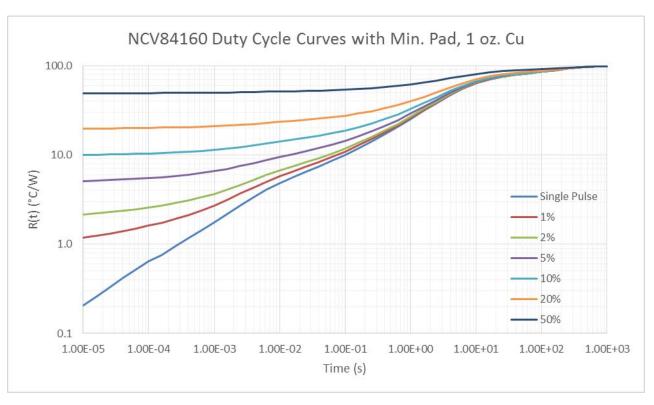


Figure 19. Junction to Ambient Transient Thermal Impedance (Min. Pad Cu Area)

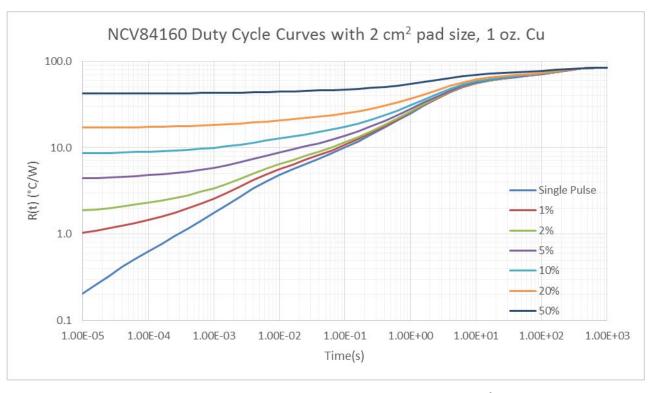
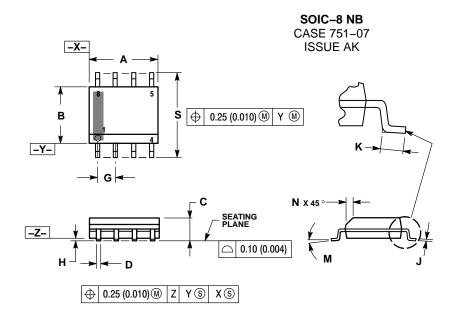
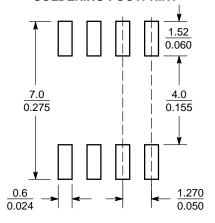


Figure 20. Junction to Ambient Transient Thermal Impedance (2 cm² Cu Area)

PACKAGE DIMENSIONS



SOLDERING FOOTPRINT



SCALE 6:1

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

NOTES

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
- MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE
- PER SIDE.

 DIMENSION D DOES NOT INCLUDE DAMBAR
 PROTRUSION. ALLOWABLE DAMBAR
 PROTRUSION SHALL BE 0.127 (0.005) TOTAL
 IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION
- 751-01 THRU 751-06 ARE OBSOLETE. NEW STANDARD IS 751-07.

	MILLIN	IETERS	INCHES		
DIM	MIN	MAX	MIN	MAX	
Α	4.80	5.00	0.189	0.197	
В	3.80	4.00	0.150	0.157	
С	1.35	1.75	0.053	0.069	
D	0.33	0.51	0.013	0.020	
G	1.27 BSC		0.050 BSC		
Н	0.10	0.25	0.004	0.010	
J	0.19	0.25	0.007	0.010	
K	0.40	1.27	0.016	0.050	
М	0 °	8 °	0 °	8 °	
N	0.25	0.50	0.010	0.020	
S	5.80	6.20	0.228	0.244	

STYLE 11:

PIN 1. SOURCE 1

- 2 GATE 1
- SOURCE 2 3.
- GATE 2 DRAIN 2
- DRAIN 2
- DRAIN 1
- DRAIN 1

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